

FCC TEST REPORT

APPLICANT

CONVERGENCE SYSTEMS LIMITED

PRODUCT NAME

: RFID Reader

MODEL NAME

CS468-2INT

TRADE NAME

CSL

BRAND NAME

CSL

FCC ID

: UB4CS468INTC1GEN2

STANDARD(S)

: 47 CFR Part 15 Subpart B

TEST DATE

2014-11-27 to 2014-12-15

ISSUE DATE

SHENZHEN MORLAB COMMUNICATIONS TECHNOLOGY Co., Ltd.

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DIRECTORY

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	Change History						
Issue Date Reason for change							
1.0	2014-12-16	First edition					
ORL	Mo.	TLAG CORLE MOTOR OF TLAG CORLE					



Test Report Declaration

Applicant	CONVERGENCE SYSTEMS LIMITED				
Applicant Address	20/F, Chung Nam Building, No.1 Lockhart Road, Wancha Hong Kong				
Manufacturer	DongGuan DongHongXingYe Electronics Science and Technology Limited				
Manufacturer Address	1 Jianxiang Street, Hanxishui, Chashan Town Dongguan, Guangdong, China				
Product Name	RFID Reader				
Model Name	CS468-2INT				
Brand Name	CSL				
HW Version	4.0				
SW Version	1.5.27				
Test Standards	47 CFR Part 15 Subpart B				
Test Result	PASS				

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Dec.16.2014

Xiao Xiong Reviewed by

Dec.16.2014

Approved by Dec.16.2014



1. Technical Information

Note: Provide by applicant.

1.1. Applicant Information

Company: CONVERGENCE SYSTEMS LIMITED

Address: 20/F, Chung Nam Building, No.1 Lockhart Road, Wanchai, Hong Kong

1.2. Equipment under Test (EUT) Description

EUT Type:	RFID Reader
Serial No:	(n.a., marked #1 by test site)
Hardware Version:	4.0
Software Version:	1.5.27

IIIO.	Ancillary	AC Adapter (Char	ger for Battery)
9	Equipment:	Brand Name:	Yunsheng
-B		Model No.:	YD04-120250D
RLL		Serial No.:	(n.a. marked #1 by test site)
6		Rated Input:	~ 100-240V, 50/60Hz, 1000mA
ORLIN	MO	Rated Output:	= 12V, 2500mA

NOTE:

1. The EUT is a RFID Reader which supports 902~928MHz ISM band, the ports of the EUT are shown as follow:







2. For a more detailed description, please refer to Specification or User's Manual supplied by the applicant and/or manufacturer.



2. Test Results

2.1. Applied Reference Documents

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title
1	47 CFR Part 15(10-1-13 Edition)	Radio Frequency Devices

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Result
1	15.107	Conducted Emission	PASS
2	15.109	Radiated Emission	PASS

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4-2009.



3. Test Conditions Setting

3.1. Test Mode

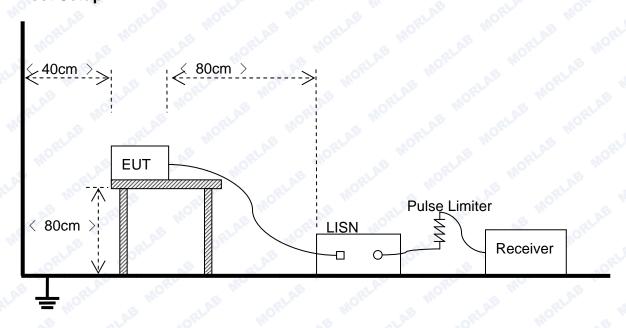
108	The first test mode (Ethernet)				
Res	The EUT configuration of the emission tests is EUT + Adapter + PC.				
RLA	During the measurement, the EUT was powered by its adapter and connected with a				
Mo	PC via the Ethernet port, the data is transmitting between the PC and the EUT, the				
-11	EUT was kept working normally as a unintentional device.				
2	The second test mode (USB)				
RI	The EUT configuration of the emission tests is EUT + Adapter + PC.				
RLA	During the measurement, the EUT was powered by its adapter and connected with a				
	PC via the Mini USB port, the data is transmitting between the PC and the EUT, the				
	EUT was kept working normally as a unintentional device.				
Note: A	Il test modes are performed, only the worst case(Ethernet) is recorded in this report.				



3.2. Test Setup and Equipments List

3.2.1. Conducted Emission

A. Test Setup:



The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu H$ of coupling impedance for the measuring instrument. A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

B. Equipments List:

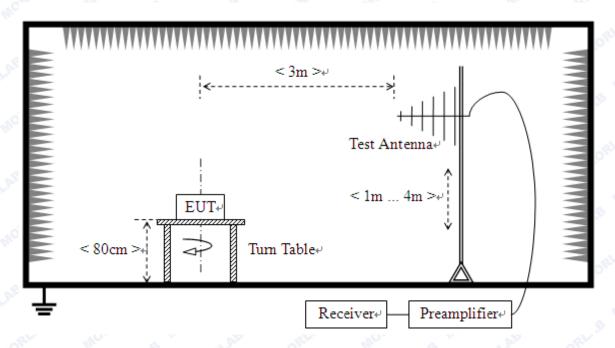
Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
Receiver	Narda	PMM 9010	595WX11007	2014.2.21	2015.2.20
EMC Analyzer	Agilent	E7405A	US44210471	2014.2.21	2015.2.20
LISN	Schwarzbeck	NSLK 8127	812744	2014.2.24	2015.2.23
Pulse Limiter (20dB)	Schwarzbeck	VTSD 9561-D	9391	(n.a.)	(n.a.)
System Simulator	Agilent	E5515C	GB43130131	2014.2.21	2015.2.20
PC	Lenovo	ThinkPadT61	ZZF3077	(n.a.)	(n.a.)



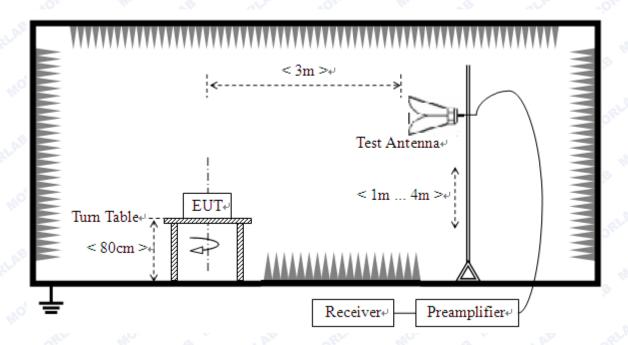
3.2.2. Radiated Emission

A. Test Setup:

1. For radiated emissions from 30MHz to1GHz



2. For radiated emissions above 1GHz





The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower.

For the test Antenna:

In the frequency range above 30MHz, Bi-Log Test Antenna (30MHz to 1GHz) and Horn Test Antenna (above 1GHz) are used. Test Antenna is 3m away from the EUT. Test Antenna height is varied from 1m to 4m above the ground to determine the maximum value of the field strength. The emission levels at both horizontal and vertical polarizations should be tested.

B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
EMC Analyzer	Agilent	E7405A	US44210471	2014.2.21	2015.2.20
Receiver	Narda	PMM 9060	001WX11001	2014.2.21	2015.2.20
Receiver	Narda	PMM 9010	595WX11007	2014.2.21	2015.2.20
Semi-Anechoic Chamber	Albatross	9m*6m*6m	(n.a.)	2014.2.21	2015.2.20
Test Antenna - Bi-Log	Schwarzbeck	VULB 9163	9163-274	2014.2.25	2015.2.24
Test Antenna - Horn	Schwarzbeck	BBHA 9120D	9120D-963	2014.2.25	2015.2.24
PC	Lenovo	ThinkPadT61	ZZF3077	(n.a.)	(n.a.)



4. 47 CFR Part 15B Requirements

4.1. Conducted Emission

4.1.1. Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a $50\mu H/50\Omega$ line impedance stabilization network (LISN).

Frequency range	Conducted Limit (dBµV)				
(MHz)	Quasi-peak	Average			
0.15 - 0.50	66 to 56	56 to 46			
0.50 - 5	56	46			
5 - 30	60	50			

NOTE:

- a) The limit subjects to the Class B digital device.
- b) The lower limit shall apply at the band edges.
- c) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50MHz.

4.1.2. Test Description

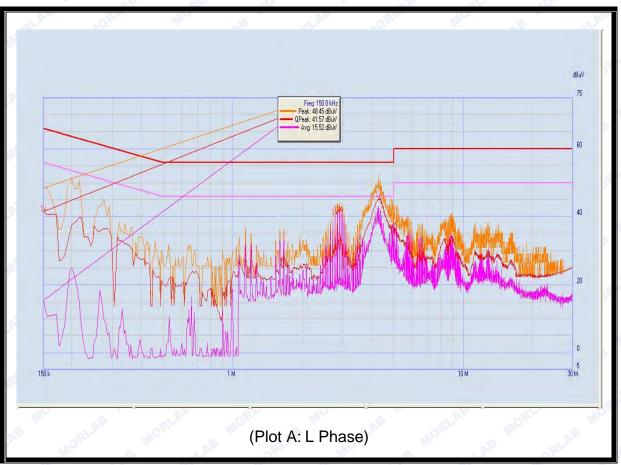
See section 3.2.1 of this report.

4.1.3. Test Result

The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

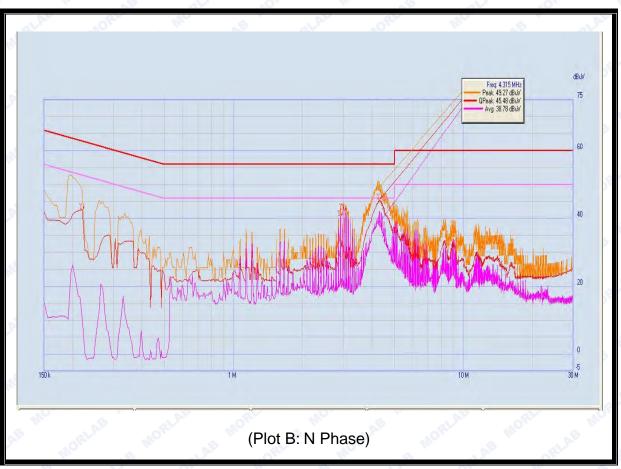
A. Test Plot and Suspicious Points:





NO.	Fre.	(-)		Limit (d	dΒμV)	Power-line	Verdict
	(MHz)	Quai-peak	Average	Quai-peak	Average		
1	0.15	41.57	15.52	66.00	56.00	ORLA	PASS
2	2.775	40.42	40.39	56.00	46.00	, we want	PASS
3	2.835	41.22	41.19	56.00	46.00	Lino	PASS
4	2.9	41.59	41.56	56.00	46.00	Line	PASS
5	2.965	41.18	41.15	56.00	46.00	Jen Bur	PASS
6	4.285	45.09	43.04	56.00	46.00	ORLAN	PASS





NO.	Fre.	Emission Level (dBµV)		Limit (dBμV)	Power-line	Verdict
1,0.	(MHz)	Quai-peak	Average	Quai-peak	Average		7010.01
1	0.22	42.68	10.36	64.00	54.00	ORLA	PASS
2	2.905	40.70	40.66	56.00	46.00	e me	PASS
3	2.965	42.69	42.66	56.00	46.00	Maystral	PASS
4	3.03	42.47	42.45	56.00	46.00	Neutral	PASS
5	3.09	41.03	41.00	56.00	46.00	Okr B W	PASS
6	4.315	45.48	38.78	56.00	46.00	ORLAN	PASS

Test Result: PASS



4.2. Radiated Emission

4.2.1. Requirement

According to FCC section 15.109(a), the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency	Field St	rength		ion at 3m Measurement ist
range (MHz)	μV/m	Dist	(μV/m)	(dBµV/m)
30.0 - 88.0	100	3m	100	20log 100
88.0 - 216.0	150	3m	150	20log 150
216.0 - 960.0	200	3m	200	20log 200
Above 960.0	500	3m	500	20log 500

As shown in FCC section 15.35(b), for frequencies above 1000MHz, the field strength limits are based on average detector. When average radiated emission measurements are specified in this part, including emission measurements below 1000MHz, there also is a limit on the radio frequency emissions, as measured using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit for the frequency being investigated unless a different peak emission limit is otherwise specified in the rules.

Note:

- 1) The tighter limit shall apply at the boundary between two frequency range.
- 2) Limitation expressed in dBμV/m is calculated by 20log Emission Level(μV/m).
- If measurement is made at 3m distance, then F.S Limitation at 3m distance is adjusted by using the formula of Ld1 = Ld2 * (d2/d1)^{2.}

Example:

F.S Limit at 30m distance is $30\mu\text{V/m}$, then F.S Limitation at 3m distance is adjusted as Ld1 = L1 = $30\mu\text{V/m}$ * $(10)^2$ = 100 * $30\mu\text{V/m}$

4.2.2. Test Description

See section 3.2.2 of this report.





4.2.3. Frequency range of measurement

Highest frequency generated or used in the device is the highest speed of the processor, lowest frequency generated or used in the device is the lowest frequency of the oscillator. According to 15.33(b)(1), the frequency range of radiated measurement for the EUT is listed in the following table:

Frequency	Frequency generated or used in the device	Frequency range of radiated measurement in the report
Highest	48MHz	1GHz

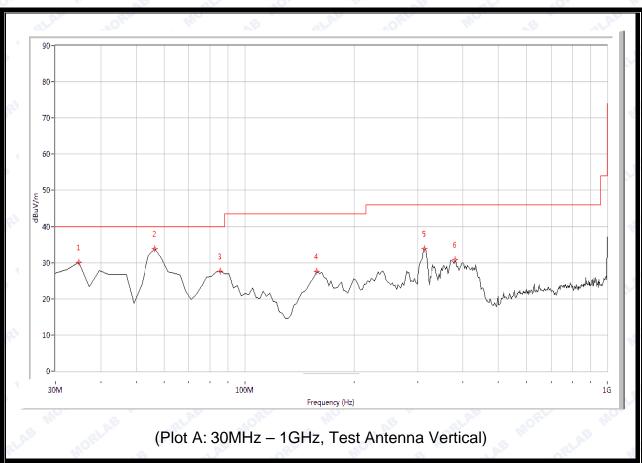
4.2.4. Test Result

The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

The amplitude of spurious emissions which are attenuated more than 20 dB below the permissible value need not be reported.

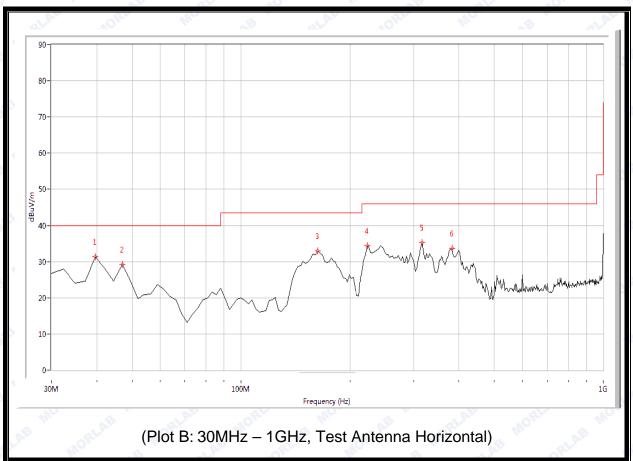
A. Test Plots and Suspicious Points:





NO.	Fre. (MHz)	Pk	QP	AV	Limit-	Limit-	Limit-	Antenna	Verdict
	LAB	ORLAN		.0	PK	QP	AV	Moles	B
1	34.838	N.A	30.13	N.A	N.A	40.0	N.A	Vertical	Pass
2	56.608	N.A	33.81	N.A	N.A	40.0	N.A	Vertical	Pass
3	85.636	N.A	27.71	N.A	N.A	40.0	N.A	Vertical	Pass
4	158.204	N.A	27.59	N.A	N.A	43.5	N.A	Vertical	Pass
5	313.017	N.A	33.90	N.A	N.A	46.0	N.A	Vertical	Pass
6	380.748	N.A	30.78	N.A	N.A	46.0	N.A	Vertical	Pass





NO.	Fre. (MHz)	Pk	QP	AV	Limit-	Limit-	Limit-	Antenna	Verdict
	RLAI MO	i.	S WILL		PK	QP	AV	3 MC	3
1	39.676	N.A	31.33	N.A	N.A	40.0	N.A	Horizontal	Pass
2	46.933	N.A	29.23	N.A	N.A	40.0	N.A	Horizontal	Pass
3	163.042	N.A	32.96	N.A	N.A	43.5	N.A	Horizontal	Pass
4	223.516	N.A	34.36	N.A	N.A	46.0	N.A	Horizontal	Pass
5	315.436	N.A	35.20	N.A	N.A	46.0	N.A	Horizontal	Pass
6	383.167	N.A	33.66	N.A	N.A	46.0	N.A	Horizontal	Pass

Test Result: PASS



Annex A Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Í	Uncertainty of Conducted Emission:	±1.8dB
Ī	Uncertainty of Radiated Emission:	±3.1dB





Annex B Testing Laboratory Information

1. Identification of the Responsible Testing Laboratory

Company Name:	Shenzhen Morlab Communications Technology Co., Ltd.
Department:	Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District, ShenZhen, GuangDong Province, P. R. China
Responsible Test Lab Manager:	Mr. Su Feng
Telephone:	+86 755 36698555
Facsimile:	+86 755 36698525

2. Identification of the Responsible Testing Location

Name:	Shenzhen Morlab Communications Technology Co., Ltd.
Address:	Morlab Laboratory FL.3, Building A, FeiYang Science Park, No.8 LongChang
	Road, Block 67, BaoAn District, ShenZhen, GuangDong
	Province, P. R. China

3. Accreditation Certificate

Accredited Testing Laboratory: CNAS No. L3572

(Shenzhen Morlab Communications Technology Co., Ltd.)

4. Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	15 - 35
Relative Humidity (%):	30 - 60
Atmospheric Pressure (kPa):	86 - 106

